



Test Report

Test Report Identifier:

SC_0195-0018-001

Tested Device:

GSM/GPRS Terminal Equipment – GE864

According to the standard:

3GPP TS 51.010-1

**GSM/GPRS Phase 2+ conformance specification (EGSM, R-GSM,
GSM900, 1800 and 1900 MHz)**

Sicom test s.r.l.

Via Dante, 5

34122 Trieste

Italy

1. General information

Test Standard: part of 3GPP TS 51.010-1 GSM/GPRS Phase 2+ conformance specification (EGSM, R-GSM, GSM900, 1800 and 1900 MHz)

Tested Device: GSM/GPRS Terminal Equipment – GE864
IMEI: 357022009999080
HW version: 1
SW version: PS:05.03.02 / AL:7.01.002-B13-GE864-QUAD

Date of Report: 2 February

Test site: Sicom test s.r.l
AREA Science Park
Loc. Padriciano, 99
Palazzina E3
34012 Trieste Italy

Client: Telit Communications S.p.A.
Viale Stazione di Prosecco 5/B
34010 Sgonico (TS)
Italy

Contact Person: Andrea Fragiacomò

This test report shall not be reproduced except in full.

Total number of pages: 3

This test report includes the following sections:

1. General information
2. Test equipment and test conditions
3. Summary of results
4. Photographs

1.1 Interpretation of test report

The results of the inspection are described on the following pages, where “Pass” in the summary list means that the test purposes were verified and that the tested device is conformant to the applied standards.

In cases where “Fail” is printed, the test purposes were not verified and the tested device is not conformant to the applied standards.

In cases where “Declaration” is printed, the required documents are available in the manufacturers product documentation.

In cases where “Not Applicable” is printed in above mentioned summary list, the test case requirements are not relevant to the specific terminal equipment implementation.

Test Operator: Andrea Lucaroni



Technical responsible: Roberto Passini



2. Test equipment and test conditions

Test Equipment:

1. Type: System Simulator
 Manufacturer: Rohde & Schwarz
 Model: TS8916B
 Serial Number: 338383/001

Instrument Type	Model	Manufacturer	Serial Number
Audio Analyzer	UPL 16	Rohde & Schwarz	825276/008
AF Amplifier (NEXUS Conditioning Ampl.)	2690	Bruel & Kjaer	2099304
Analog Background Unit	CRTC AU	Rohde & Schwarz	845412/003
Analog Background Unit	CRTC AU 2	Rohde & Schwarz	843539/006
Analog Background Unit	CRTC AU 3	Rohde & Schwarz	839383/002
Digital Background Unit	CTRC DU	Rohde & Schwarz	825501/010
Ear Simulator	4185	Bruel & Kjaer	1826832
Fading Simulator	SOFI05	Sofimation OY	181
Tester GSM-DCS-PCS Master	CRTC02-AU	Rohde & Schwarz	843539/010
Tester GSM-DCS-PCS Master	CRTC02-DU	Rohde & Schwarz	843350/004
Tester GSM-DCS-PCS Slave	CRTC02-AU	Rohde & Schwarz	844043/020
Tester GSM-DCS-PCS Slave	CRTC02-DU	Rohde & Schwarz	844929/002
Mouth Simulator	4227	Bruel & Kjaer	1831219
Power Meter	NRVD	Rohde & Schwarz	843789/040
Power Supply	NGPE40	Rohde & Schwarz	0683
Sensor Head A	NRV-Z1	Rohde & Schwarz	841112/005
Sensor Head B	NRV-Z1	Rohde & Schwarz	842147/015
Signal Generator	SME03	Rohde & Schwarz	844395/007
Signal Generator	SMP02	Rohde & Schwarz	830185/001
Sound level calibrator	4231	Bruel & Kjaer	1839379
Spectrum Analyzer	FSIQ26	Rohde & Schwarz	s/n 827773/004
Test Head	4602B	Bruel & Kjaer	---

2. Type: GSM-DCS-PCS Tester
Manufacturer: Rohde & Schwarz
Model: CRTC02
Serial Number: AU 843539/006 – DU 843350/006

3. Type: Temperature Test Chamber
Manufacturer: VÖTSCH
Model: VT 4002
Serial Number: 521/83675

4. Type: DC Power Supply
Manufacturer: Hewlett Packard
Model: HP E3632A
Serial Number: KR73001004

Test Conditions:

The testing has been performed within the period:

From: 30 January 2006
To: 1 February 2006

Conditions:

Humidity: 25% - 75% HR

Normal temperature: +15°C - +35°C
High temperature: +55°C ± 1°C
Low temperature: -10°C ± 1°C

Nominal voltage: 3.8 V
High voltage: 4.2 V
Low voltage: 3.4 V

3. Summary of results

Test ID	Test title	Result
21.1_HTHV_1800	Received signal measurements: Signal Strength	Pass
21.1_HTHV_900	Received signal measurements: Signal Strength	Pass
21.1_HTHV_900+1800	Received signal measurements: Signal Strength	Pass
21.1_HTLV_1800	Received signal measurements: Signal Strength	Pass
21.1_HTLV_900	Received signal measurements: Signal Strength	Pass
21.1_HTLV_900+1800	Received signal measurements: Signal Strength	Pass
21.1_LTHV_1800	Received signal measurements: Signal Strength	Pass
21.1_LTHV_900	Received signal measurements: Signal Strength	Pass
21.1_LTHV_900+1800	Received signal measurements: Signal Strength	Pass
21.1_LTLV_1800	Received signal measurements: Signal Strength	Pass
21.1_LTLV_900	Received signal measurements: Signal Strength	Pass
21.1_LTLV_900+1800	Received signal measurements: Signal Strength	Pass
21.1_NC_1800	Received signal measurements: Signal Strength	Pass
21.1_NC_900	Received signal measurements: Signal Strength	Pass
21.1_NC_900+1800	Received signal measurements: Signal Strength	Pass
21.2_1800	Received signal measurements: Signal Strength selectivity	Pass
21.2_900	Received signal measurements: Signal Strength selectivity	Pass

Note: the observed values are available on request at our laboratory.

4. Photographs



Picture 1 Tested Device



Picture 2 Tested Device placed on the evaluation board